DSK3J02

Silicon N-channel Junction FET

For impedance conversion in low frequency

Features

- Low noise voltage NV
- Contributes to miniaturization of sets, reduction of component count.
- Eco-friendly Halogen-free package

Packaging

Embossed type (Thermo-compression sealing): 10000 pcs / reel (standard)

Absolute Maximum Ratings $T_a = 25^{\circ}C$

Parameter	Symbol	Rating	Unit
Drain-source voltage (Gate open)	V _{DSO}	20	V
Drain-gate voltage (Souece open)	V _{DGO}	V	
Drain-source current (Gate open)	I _{DSO}	2	mA
Drain-gate current (Souece open)	I _{DGO}	2	mA
Power dissipation	PD	100	mW
Operating ambient temperature	T _{opr}	-20 to +80	°C
Storage temperature	T _{stg}	-55 to +150	°C

Package

- Code
- SSSMini3-F2-B
- Pin Name
 - 1: Drain
 - 2: Source
 - 3: Gate

Marking Symbol: 3

Electrical Characteristics	$T_a = 25^{\circ}C \pm 3^{\circ}C$
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Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain current ^{*1}	ID	$V_{DS} = 2.0 \text{ V}, R_d = 2.2 \text{ k}\Omega \pm 1\%$	100		470	μΑ
Drain-source cutoff current *2	I _{DSS}	$V_{DS} = 2.0 \text{ V}, R_d = 2.2 \text{ k}\Omega \pm 1\%, V_{GS} = 0$	110		460	μΑ
Forward transfer admittance	Y _{fs}	$V_D = 2.0 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	660	1 500		μS
Noise voltage *3	NV	$V_D = 2.0 \text{ V}, R_d = 2.2 \text{ k}\Omega \pm 1\%,$ $C_O = 5 \text{ pF}, \text{A-curve}$			4	μV
Voltage gain	G _{V1}	$V_D = 2.0 \text{ V}, R_d = 2.2 \text{ k}\Omega \pm 1\%,$ $C_O = 5 \text{ pF}, eG = 10 \text{ mV}, f = 1 \text{ kHz}$	-5.0	-1.0		dB
	G _{V2}	$V_D = 1.5 \text{ V}, R_d = 2.2 \text{ k}\Omega \pm 1\%,$ $C_O = 5 \text{ pF}, eG = 10 \text{ mV}, f = 1 \text{ kHz}$	-7.0	-1.5		dB
	$\Delta \big G_V . f \big {}^{*4}$	$V_D = 2.0 \text{ V}, R_d = 2.2 \text{ k}\Omega \pm 1\%,$ $C_O = 5 \text{ pF}, eG = 10 \text{ mV}, f = 1 \text{ kHz to } 70 \text{ Hz}$		0	1.7	dB
Voltage gain difference	G _{V1} -G _{V2}		0		2.0	dB

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. A protection diode is built-in between gate and source of transistor. However if forward current flows between gate and source transistor might be damaged. So please be careful not insert reverse.

3. *1: $I_{D}\xspace$ is assured for $I_{DSS}\xspace$

*2: Rank classification

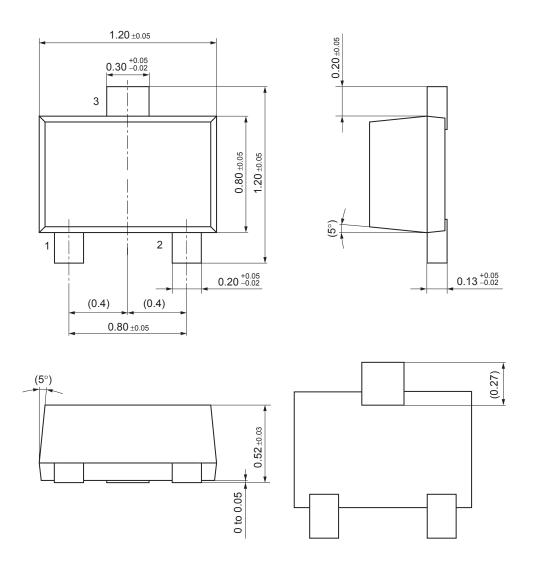
Code	S	Т	U
Rank	S	Т	U
I _D (μA)	100 to 220	180 to 320	280 to 470
I_{DSS} (μA)	110 to 210	190 to 310	290 to 460
Marking Symbol	38	3T	3U

*3: NV is assured for design.

*4: $\Delta | G_V$. f | is assured for AQL 0.065%. (The measurement method is used by source-grounded circuit.)

SSSMini3-F2-B

Unit: mm



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